

**Search Notes**

Application/Control No.

10/695,022

Examiner

Cheukfan Lee

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2625

**SEARCHED**

Class	Subclass	Date	Examiner
358	497	9/11/2007	C.L.
	493		
	474		
	505		
	483		
	482		
	512-514		
250	208.1		
	239		
	234-236		
399	211		
382	312		
	318,319		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search: see reuslt	9/11/2007	C.L.
Inventor search		
Reference only: Yoshida (5,392,100), Hasegawa et al. (6,438,350), Fujioka et al. (5,583,607), Fujioka et al. (5,471,277)		